Search Notes

Application/Control No.	Applicant(s)/Patent under Reexamination
10/840,192	FUJIKAWA ET AL.
Examiner	Art Unit
EDMUND H. LEE	1791

CEARCHER						
SEARCHED						
Subclass	Date	Examiner				
		SEARCHED  Subclass Date				

INTERFERENCE SEARCHED					
Class	Subclass	Date	Examiner		
264	259,255	3/30/2009	EHL		
264	319,293	3/30/2009	EHL		
264/	220	3/30/2009	EHL		

SEARCH N (INCLUDING SEAR)		)
	DATE	EXMR
264/259,255,319,293,220	3/30/2009	EHL
EAST	3/30/2009	EHL